

#### Description

The AP3P06Al uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



 $V_{DS} = -60V I_{D} = -3 A$ 

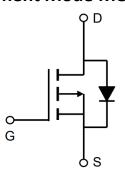
 $R_{DS(ON)}$  < -180m $\Omega$  @  $V_{GS}$ =-10V

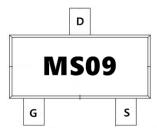
#### **Application**

**Battery protection** 

Load switch

Uninterruptible power supply







**Package Marking and Ordering Information** 

| Product ID | Pack   | Marking | Qty(PCS) |
|------------|--------|---------|----------|
| AP3P06AI   | SOT-23 | MS09    | 3000     |

#### Absolute Maximum Ratings (T<sub>C</sub>=25°Cunless otherwise noted)

| Symbol                               | Parameter   | Rating     | Units |
|--------------------------------------|---|------------|-------|
| VDS                                  | Drain-Source Voltage  | -60        | V     |
| Vgs                                  | Gate-Source Voltage   | ±20        | V     |
| I <sub>D</sub> @T <sub>A</sub> =25°C | Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup> | -3.3       | Α     |
| I <sub>D</sub> @T <sub>A</sub> =70°C | Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup> | -1.4       | А     |
| Іом                                  | Pulsed Drain Current <sup>2</sup>                             | -7         | А     |
| P <sub>D</sub> @T <sub>A</sub> =25°C | Total Power Dissipation <sup>3</sup>                          | 1          | W     |
| Тѕтс                                 | Storage Temperature Range                                     | -55 to 150 | °C    |
| T <sub>J</sub>                       | Operating Junction Temperature Range                          | -55 to 150 | °C    |
| R <sub>θ</sub> JA                    | Thermal Resistance Junction-Ambient <sup>1</sup>              | 125        | °CMV  |
| R <sub>θ</sub> JC                    | Thermal Resistance Junction-Case <sup>1</sup>                 | 80         | °CM   |



### **Electrical Characteristics (Tc=25**<sup>o</sup>Cunless otherwise noted)

| Symbol                     | Parameter                                      | Conditions   | Min. | Тур.   | Max. | Unit |
|----------------------------|--|--|------|--------|------|------|
| BVDSS                      | Drain-Source Breakdown Voltage                 | V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA                           | -60  |        |      | V    |
| △BVɒss/△Tɹ                 | BV <sub>DSS</sub> Temperature Coefficient      | Reference to 25℃ , I <sub>D</sub> =-1mA                                |      | -0.021 |      | V/℃  |
| Б                          | Static Drain-Source On-Resistance <sup>2</sup> | V <sub>GS</sub> =-10V , I <sub>D</sub> =-1.5A                          |      | 130    | 185  | mΩ   |
| RDS(ON)                    |  | V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-1A                           |      | 158    | 200  |      |
| V <sub>G</sub> S(th)       | Gate Threshold Voltage                         | $V_{GS}=V_{DS}$ , $I_D=-250uA$   | -1.0 |        | -2.5 | V    |
| $\triangle V_{GS(th)}$     | V <sub>GS(th)</sub> Temperature Coefficient    | V GS - V DS , 1D - 2000/   |      | 4.08   |      | mV/℃ |
| loss                       | Drain-Source Leakage Current                   | $V_{DS}$ =-48V , $V_{GS}$ =0V , $T_{J}$ =25 $^{\circ}$ C               |      |        | 1    | ۸    |
| 1055                       |  | V <sub>DS</sub> =-48V , V <sub>GS</sub> =0V , T <sub>J</sub> =55℃      |      |        | 5    | uA   |
| Igss                       | Gate-Source Leakage Current                    | V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V                            |      |        | ±100 | nA   |
| gfs                        | Forward Transconductance                       | V <sub>DS</sub> =-5V , I <sub>D</sub> =-1.5A                           |      | 5.9    |      | S    |
| $Q_g$                      | Total Gate Charge (-4.5V)                      | V <sub>DS</sub> =-20V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-1.5A |      | 4.6    |      |      |
| Qgs                        | Gate-Source Charge                             |  |      | 1.4    |      | nC   |
| $\mathbf{Q}_{\mathrm{gd}}$ | Gate-Drain Charge                              |  |      | 1.62   |      |      |
| Td(on)                     | Turn-On Delay Time                             |  |      | 17.4   |      |      |
| T <sub>r</sub>             | Rise Time                                      | $V_{DS}$ =-15V , $V_{GS}$ =-10V , $R_{G}$ =3.3 $\Omega$ .              |      | 5.4    |      |      |
| Td(off)                    | Turn-Off Delay Time                            | I <sub>D</sub> =-1A  |      | 37.2   |      | ns   |
| T <sub>f</sub>             | Fall Time                                      |  |      | 2.4    |      |      |
| Ciss                       | Input Capacitance                              |  |      | 531    |      |      |
| Coss                       | Output Capacitance                             | V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , f=1MHz                   |      | 59     |      | pF   |
| Crss                       | Reverse Transfer Capacitance                   |  |      | 38     |      |      |
| ls                         | Continuous Source Current <sup>1,4</sup>       | V V 0V 5   |      |        | -1.7 | Α    |
| lsм                        | Pulsed Source Current <sup>2,4</sup>           | · V <sub>G</sub> =V <sub>D</sub> =0V , Force Current                   |      |        | -7   | Α    |
| Vsp                        | Diode Forward Voltage <sup>2</sup>             | V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25℃        |      |        | -1.2 | V    |

#### Note:

<sup>1.</sup>The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.

<sup>2.</sup>The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%

<sup>3.</sup>The power dissipation is limited by 150°C junction temperature

<sup>4.</sup> The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



### **Typical Characteristics**

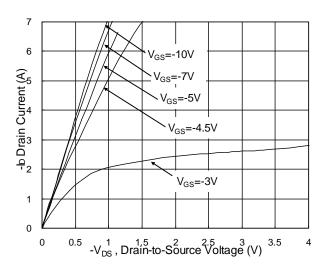


Fig.1 Typical Output Characteristics

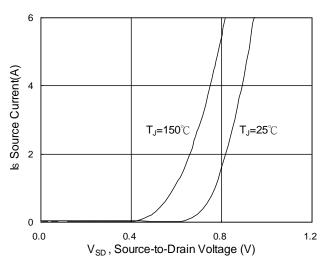


Fig.3 Forward Characteristics Of Reverse

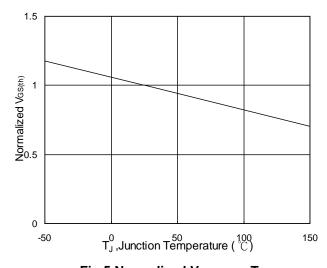


Fig.5 Normalized  $V_{\text{GS(th)}} \ v.s \ T_J$ 

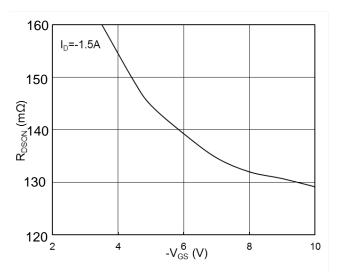


Fig.2 On-Resistance v.s Gate-Source

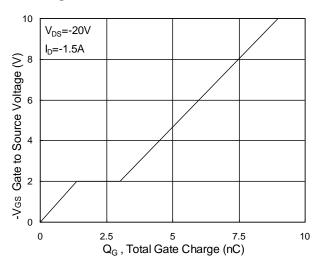


Fig.4 Gate-Charge Characteristics

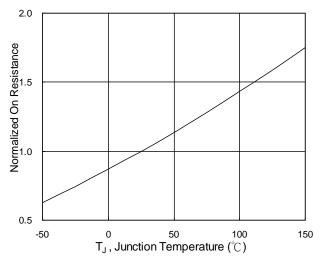
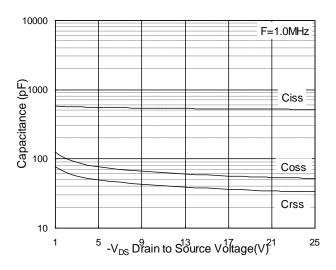


Fig.6 Normalized R<sub>DSON</sub> v.s T<sub>J</sub>







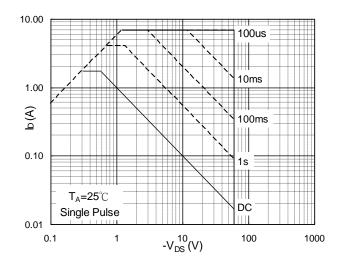


Fig.7 Capacitance

Fig.8 Safe Operating Area

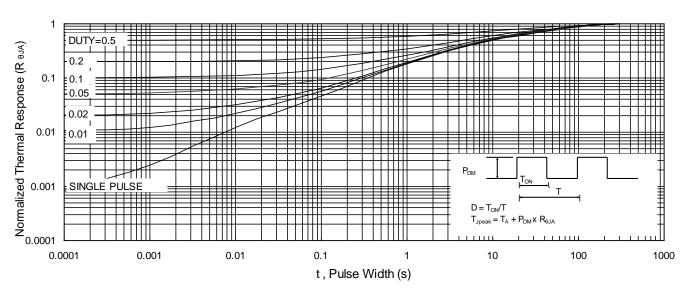
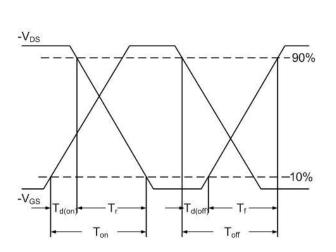
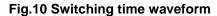


Fig.9 Normalized Maximum Transient Thermal Impedance





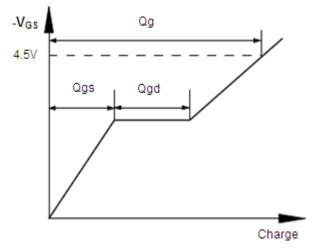
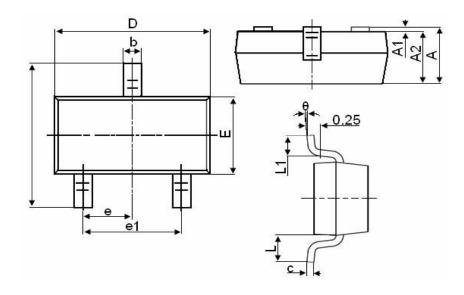


Fig.11 Gate Charge waveform



# Package Mechanical Data-SOT-23



| Suma la al | Dimensions in Millimeters |       |  |
|------------|---------------------------|-------|--|
| Symbol     | MIN.                      | MAX.  |  |
| А          | 0.900                     | 1.150 |  |
| A1         | 0.000                     | 0.100 |  |
| A2         | 0.900                     | 1.050 |  |
| b          | 0.300                     | 0.500 |  |
| С          | 0.080                     | 0.150 |  |
| D          | 2.800                     | 3.000 |  |
| E          | 1.200                     | 1.400 |  |
| E1         | 2.250                     | 2.550 |  |
| е          | 0.950TYP                  |       |  |
| e1         | 1.800                     | 2.000 |  |
| L          | 0.550REF                  |       |  |
| L1         | 0.300                     | 0.500 |  |
| θ          | 0°                        | 8°    |  |



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| Edition | Date      | Change          |
|---------|-----------|-----------------|
| Rve3.7  | 2019/4/10 | Initial release |
| Rve3.9  | 2020/3/25 | Reduce RDS(on)  |

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# Test Report For 30PCS (30pcs 典型測試報告)

